## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination HO ET AL. Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,617,681 B1	09-2003	Bohr, Mark T.	257/700
	В	US-6,784,554 B2	08-2004	Kajiwara et al.	257/778
	С	US-6,861,757 B2	03-2005	Shimoto et al.	257/773
	D	US-2004/0155337 A1	08-2004	Strandberg et al.	257/738
	E	US-2005/0133930 A1	06-2005	Savastisuk et al.	257/774
	F	US-2005/0136634 A1	06-2005	Savastiouk et al.	438/597
	G	US-2005/0146049 A1	07-2005	Kripesh et al.	257/776
	Н	US-2004/0090756 A1	05-2004	Ho et al.	361/767
	1	US-6,841,862 B2	01-2005	Kikuchi et al.	257/680
	J	US-6,365,975 B1	04-2002	DiStefano et al.	257/777
	K	US-6,882,045 B2	04-2005	Massingill et al.	257/724
	L	US-6,770,971 B2	08-2004	Kouno et al.	257/734
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q					
	R					
	s					
	Τ					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	٧					
	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.